

Notice of References Cited	Application/Control No. 10/605,196	Applicant(s)/Patent Under Reexamination TUNG ET AL.	
	Examiner Nha Nguyen	Art Unit 2112	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,934,886	08-2005	Ok, Jae Chul	714/34
*	B	US-2002/0065646	05-2002	Waldie et al.	703/26
*	C	US-5,978,937	11-1999	Miyamori et al.	714/45
*	D	US-2003/0037225	02-2003	Deng et al.	712/227
*	E	US-7,043,717	05-2006	Matsumoto et al.	717/124
*	F	US-6,708,289	03-2004	Kudo, Makoto	714/28
*	G	US-2002/0059560	05-2002	Phillips, Mark	717/124
*	H	US-5,943,498	08-1999	Yano et al.	717/128
*	I	US-2002/0188813	12-2002	Cheung et al.	711/154
*	J	US-5,379,301	01-1995	Sato et al.	717/124
*	K	US-6,173,419	01-2001	Barnett, Philip C.	714/28
*	L	US-6,415,393	07-2002	Satoh, Shuji	714/30
*	M	US-6,668,339	12-2003	Maeda, Shohei	714/38

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.